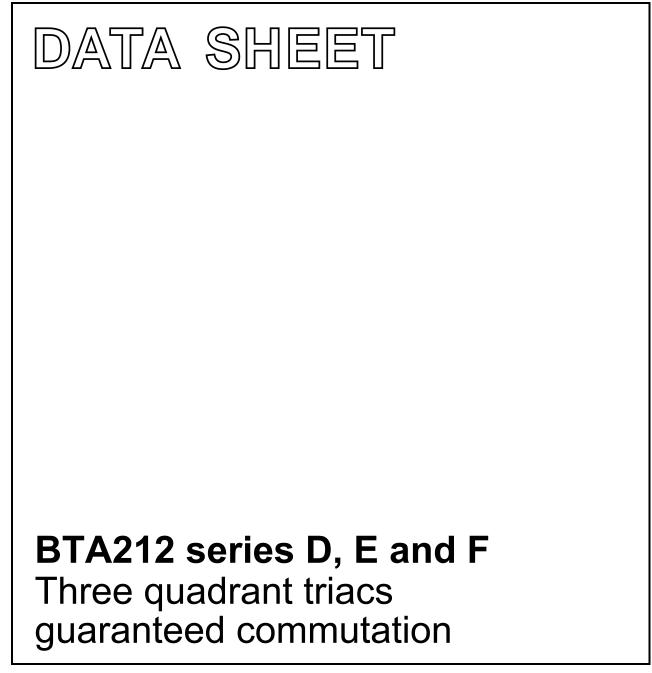
DISCRETE SEMICONDUCTORS



Product specification

June 2003



MAX.

600D

600E

600F

600

12

95

UNIT

٧

A

А

# Three quadrant triacs guaranteed commutation

# BTA212 series D, E and F

BTA212-

**BTA212-**

**BTA212-**

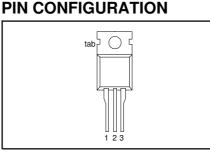
# **GENERAL DESCRIPTION**

Passivated guaranteed commutation triacs in a plastic envelope intended for use in motor control circuits or with other highly inductive loads. These devices balance the requirements of commutation performance and gate sensitivity. The "sensitive gate" E series and "logic level" D series are intended for interfacing with low power drivers, including micro controllers.

# **PINNING - TO220AB**

# PIN DESCRIPTION

# main terminal 1 main terminal 2 gate main terminal 2



QUICK REFERENCE DATA

current

PARAMETER

Repetitive peak off-state

Non-repetitive peak on-state

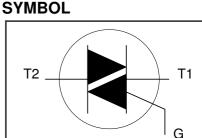
voltages RMS on-state current

SYMBOL

V<sub>DRM</sub>

T(RMS)

I<sub>TSM</sub>



# LIMITING VALUES

Limiting values in accordance with the Absolute Maximum System (IEC 134).

SYMBOL	PARAMETER	CONDITIONS	MIN.	MAX.	UNIT
V <sub>DRM</sub>	Repetitive peak off-state voltages		-	600 <sup>1</sup>	V
I <sub>T(RMS)</sub> I <sub>TSM</sub>	RMS on-state current Non-repetitive peak on-state current	full sine wave; $T_{mb} \le 99$ °C full sine wave; $T_{mb} = 25$ °C prior to	-	12	A
l²t dl⊤/dt	I <sup>2</sup> t for fusing Repetitive rate of rise of on-state current after	$\begin{array}{l} T_{j} = 25 \ ^{\circ}\text{C prior to} \\ \text{surge} \\ t = 20 \ \text{ms} \\ t = 16.7 \ \text{ms} \\ t = 10 \ \text{ms} \\ I_{\text{TM}} = 20 \ \text{A}; \ I_{\text{G}} = 0.2 \ \text{A}; \\ \text{d}_{\text{G}}/\text{d}t = 0.2 \ \text{A}/\mu\text{s} \end{array}$	- -	95 105 45 100	A A A²s A/µs
I <sub>GM</sub> P <sub>GM</sub> P <sub>G(AV)</sub>	triggering Peak gate current Peak gate power Average gate power	over any 20 ms period	- - -	2 5 0.5	A W W
T <sub>stg</sub> T <sub>j</sub>	Storage temperature Operating junction temperature		-40 -	150 125	Ĵ, Ĵ

<sup>1</sup> Although not recommended, off-state voltages up to 800V may be applied without damage, but the triac may switch to the on-state. The rate of rise of current should not exceed 15  $A/\mu s$ .

# Three quadrant triacs guaranteed commutation

# BTA212 series D, E and F

# THERMAL RESISTANCES

SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT
R <sub>th j-mb</sub> R <sub>th j-a</sub>	Thermal resistance junction to mounting base Thermal resistance junction to ambient	full cycle half cycle in free air	-	- - 60	1.5 2.0 -	K/W K/W K/W

# STATIC CHARACTERISTICS

 $T_i = 25$  °C unless otherwise stated

SYMBOL	PARAMETER	CONDITIONS	MIN.	MAX.		UNIT	
		BTA212-		D	E	F	
I <sub>GT</sub>	Gate trigger current <sup>2</sup>	$V_{\rm D} = 12 \text{ V}; \text{ I}_{\rm T} = 0.1 \text{ A}$					
-		T2+ G+	-	5 5 5	10	25	mA
		T2+ G-	-	5	10	25	mA
	Latching current	T2- G- V <sub>D</sub> = 12 V; I <sub>GT</sub> = 0.1 A	-	Э	10	25	mA
IL.		$V_D = 12 V, I_{GT} = 0.1 A$ T2+G+	_	15	20	25	mA
		T2+ G-	-	25	30	40	mA
		T2- G-	-	25	30	40	mA
I <sub>H</sub>	Holding current	$V_{\rm D} = 12 \text{ V}; \text{ I}_{\rm GT} = 0.1 \text{ A}$	-	15	25	30	mA
V <sub>T</sub>	On-state voltage	I <sub>τ</sub> = 17 A	-		1.6		V
V <sub>GT</sub>	Gate trigger voltage	$\dot{V}_{D} = 12 \text{ V}; I_{T} = 0.1 \text{ A}$	-		1.5		V
<u>.</u>		$V_{D} = 400 \text{ V}; I_{T} = 0.1 \text{ A};$ T <sub>i</sub> = 125 °C	0.25		-		V
I <sub>D</sub>	Off-state leakage current	$V_{\rm D} = V_{\rm DRM(max)}; T_{\rm j} = 125 ^{\circ}{\rm C}$	-		0.5		mA

# **DYNAMIC CHARACTERISTICS**

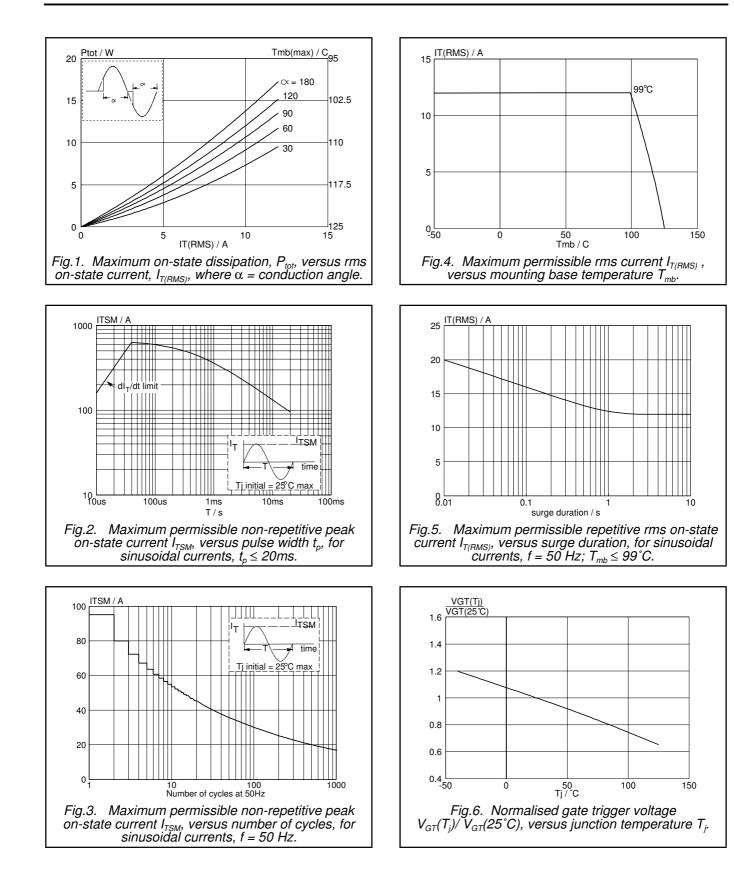
 $T_i = 25$  °C unless otherwise stated

SYMBOL	PARAMETER	CONDITIONS	MIN.		MAX.	UNIT	
		BTA212-	D	E	F		
dV <sub>D</sub> /dt	Critical rate of rise of off-state voltage	$V_{DM} = 67\% V_{DRM(max)};$ $T_j = 110 °C;$ exponential waveform; gate open circuit	30	60	70	-	V/µs
dl <sub>com</sub> /dt	Critical rate of change of commutating current	$V_{DM} = 400 \text{ V}; \text{T}_{j} = 125 \text{ °C};$ $I_{T(RMS)} = 12 \text{ A};$ $dV_{com}/dt = 10 \text{ V}/\mu\text{s}; \text{ gate}$ open circuit	1.0	8	21	-	A/ms
dl <sub>com</sub> /dt	Critical rate of change of commutating current	$\begin{array}{l} V_{\text{DM}}=400 \; V; \; T_{j}=125 \; ^{\circ}\text{C}; \\ I_{T(\text{RMS})}=12 \; \text{A}; \\ dV_{\text{com}}/dt=0.1 \; V/\mu\text{s}; \; \text{gate} \\ \text{open circuit} \end{array}$	3.5	16	32	-	A/ms

**<sup>2</sup>** Device does not trigger in the T2-, G+ quadrant.

# Three quadrant triacs guaranteed commutation

# BTA212 series D, E and F



BTA212 series D, E and F

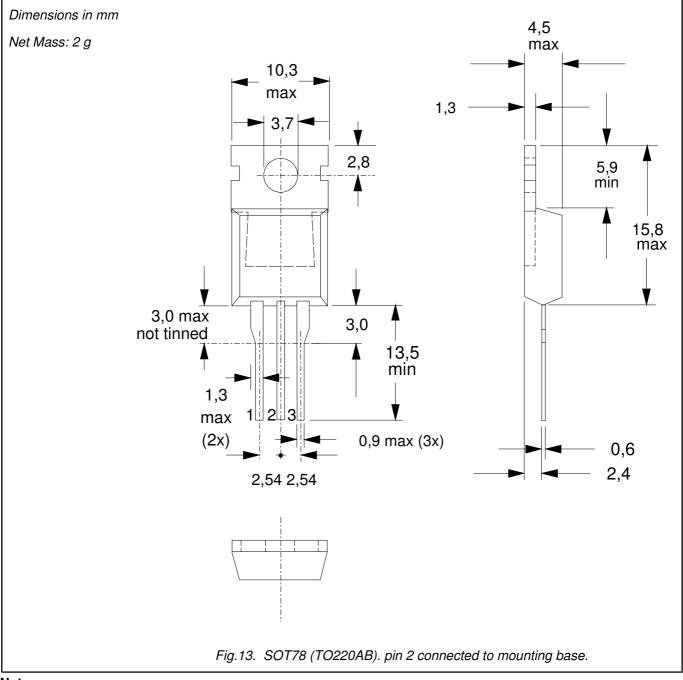
# Three quadrant triacs guaranteed commutation

#### IT / A IGT(Tj) IGT(25℃) 40 Tj = 125 C ----typ 3 — T2+ G+ — T2+ G-Tj = 25 C max - T2- G-2.5 30 Vo = 1.175 V Rs = 0.0316 Ohms 2 20 1.5 1 10 0.5 0 0 L 1.5 VT / V 0.5 2 2.5 3 -50 0 тј/℃ 100 150 Fig.7. Normalised gate trigger current $I_{GT}(T_j)/I_{GT}(25^{\circ}C)$ , versus junction temperature $T_j$ . Fig.10. Typical and maximum on-state characteristic. IL(Tj) IL(25°C) Zth j-mb (K/W) 10 3 25 unidirecti 2 ectiona 0.1 1.5 1 ■ <sup>t</sup>p <del>■</del> 0.01 0.5 0 -50 0.001 L 10us 50 Tj /℃ 0 100 150 0.1ms 1ms 10ms 0.1s 1s 10s tp/s Normalised latching current $I_L(T_i)/I_L(25^{\circ}C)$ , Fig.8. Fig.11. Transient thermal impedance $Z_{th j-mb}$ , versus pulse width $t_p$ . versus junction temperature $T_{i}$ IH(Tj) 3 IH(25°C dlcom/dt (A/ms) 10<sup>3</sup> F TYPE E TYPE 2.5 D TYPE 2 10<sup>2</sup> 1.5 10 1 0.5 1 0 -50 50 Tj /℃ 100 150 0 20 40 60 80 <sup>120</sup> T<sub>j</sub> (°C) <sup>140</sup> 100 Fig.9. Normalised holding current $I_H(T_i)/I_H(25^{\circ}C)$ , versus junction temperature $T_j$ . Fig.12. Minimum critical rate of change of commutating current $dI_{com}/dt$ versus junction temperature, $dV_{com}/dt = 10V/\mu s$ .

# Three quadrant triacs guaranteed commutation

# BTA212 series D, E and F

# **MECHANICAL DATA**



Notes 1. Refer to mounting instructions for SOT78 (TO220) envelopes. 2. Epoxy meets UL94 V0 at 1/8".

# Legal information

### DATA SHEET STATUS

DOCUMENT STATUS <sup>(1)</sup>	PRODUCT STATUS <sup>(2)</sup>	DEFINITION
Objective data sheet	Development	This document contains data from the objective specification for product development.
Preliminary data sheet	Qualification	This document contains data from the preliminary specification.
Product data sheet	Production	This document contains the product specification.

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